

# Nano-WO<sub>3</sub> film modified macro-porous silicon (MPS) gas sensor\*

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**Abstract:** We prepared macro-porous silicon (MPS) by electrochemical corrosion in a double-tank cell on the surface of single-crystalline P-type silicon. Then, nano-WO<sub>3</sub> films were deposited on MPS layers by DC facing target reactive magnetron sputtering. The morphologies of the MPS and WO<sub>3</sub>/MPS samples were investigated by using a field emission scanning electron microscope. The crystallization of WO<sub>3</sub> and the valence of the W in the WO<sub>3</sub>/MPS sample were characterized by X-ray diffraction and X-ray photoelectron spectroscopy, respectively. The gas sensing properties of MPS and WO<sub>3</sub>/MPS gas sensors were thoroughly measured at room temperature. It can be concluded that: the WO<sub>3</sub>/MPS gas sensor shows the gas sensing properties of a P-type semiconductor gas sensor. The WO<sub>3</sub>/MPS gas sensor exhibits good recovery characteristics and repeatability to 1 ppm NO<sub>2</sub>. The addition of WO<sub>3</sub> can enhance the sensitivity of MPS to NO<sub>2</sub>. The long-term stability of a WO<sub>3</sub>/MPS gas sensor is better than that of an MPS gas sensor. The sensitivity of the WO<sub>3</sub>/MPS gas sensor to NO<sub>2</sub> is higher than that to NH<sub>3</sub> and C<sub>2</sub>H<sub>5</sub>OH. The selectivity of the MPS to NO<sub>2</sub> is modified by deposited nano-WO<sub>3</sub> film.

**Key words:** MPS; WO<sub>3</sub>/MPS gas sensor; gas sensing properties; room temperature

**DOI:** 10.1088/1674-4926/33/5/054012

**PACC:** 8160C; 8280T

## 1. Introduction

With more and more contaminated gas emissions from industry and daily life, novel high-performance and low-power gas sensors have attracted increasing attention. Porous silicon (PS), which has high specific area can be used as an alternative material for gas sensors operated at room temperature<sup>[1–4]</sup>. Conductivity variation of this material is the easiest way to realize a gas sensor for gas detection. It is easy to integrate PS with current CMOS/MEMS technologies<sup>[5–8]</sup> thereby reducing the cost of devices, which is important for its practical application.

The pore diameter of PS can be controlled from tens of nanometers<sup>[9]</sup> to a few micrometers<sup>[10, 11]</sup> by changing formation parameters. Macro-porous silicon (MPS) is a kind of PS that has an average pore diameter of more than 50 nm. MPS has recently attracted the attention of the scientific community for its various applications in photonic devices<sup>[12]</sup>, micro-fuel cell electrodes<sup>[13]</sup>, supercapacitors<sup>[14]</sup>, biosensors<sup>[15]</sup> and gas sensors<sup>[16]</sup>. An MPS layer has low porosity, which results in low sensitivity when used as a gas sensor. In recent years, some researchers have deposited the modified layer on the MPS surface to improve its gas sensing properties. Kanungo *et al.*<sup>[17]</sup> produced a reliable and stable MPS hydrogen sensor working at an elevated temperature by depositing the ZnO thin film on MPS. Ozdemir and Gole<sup>[18]</sup> deposited metal oxide coatings on the MPS surface and improved the sensitivity of MPS to PH<sub>3</sub>. Galstyan *et al.*<sup>[19]</sup> developed a high sensitivity and stability hydrogen gas sensor made of MPS covered with thin metal oxide film. However, there are a few articles reporting on the improvement of the gas sensing properties of MPS to NO<sub>2</sub>.

In this work, WO<sub>3</sub> modified layers were deposited on MPS. We investigated the gas sensing properties of MPS and WO<sub>3</sub>/MPS gas sensors for detecting different concentrations of NO<sub>2</sub> at room temperature. Our study indicates that the addition of WO<sub>3</sub> can enhance the sensitivity, improve the long-term stability and modify the selectivity of the MPS to NO<sub>2</sub>.

## 2. Experimental details

MPS layers were formed by electrochemical corrosion of (100)-oriented monocrystalline P-type silicon wafers with 10–15 Ω·cm resistivity and 400 ± 10 μm thickness in a double-tank cell. The electrolyte consisted of 99.5 wt.% N, N-Dimethylformamide (DMF) and 40 wt.% hydrofluoric acid in a volume ratio of 2 : 1. The etching current density was 100 mA/cm<sup>2</sup>. The etching time for all samples was 5 min. Then the nano-WO<sub>3</sub> films were deposited on MPS layers using the dc reactive magnetron sputtering method. The deposited thin films were annealed at a temperature of 450 °C for 4 h in air. Pt electrodes were deposited on the top of the MPS and WO<sub>3</sub>/MPS to form MPS and WO<sub>3</sub>/MPS gas sensors. The sputtering conditions of different metals are shown in Table 1. The schematic diagrams of the MPS and WO<sub>3</sub>/MPS gas sensors are shown in Fig. 1.

The surface and cross-section images of MPS and WO<sub>3</sub>/MPS samples were obtained by using a field emission scanning electron microscope (FESEM, Nanosem 430). The crystallization of WO<sub>3</sub> and the valence of the W in the WO<sub>3</sub>/MPS sample were respectively characterized by X-ray diffraction (XRD, D/MAX 2500) and X-ray photoelectron spectroscopy (XPS, PHI-1600). Gas sensing characteristics of MPS and WO<sub>3</sub>/MPS gas sensors were measured at room tem-

\* Project supported by the National Natural Science Foundation of China (No. 60771019) and the Tianjin Key Research Program of Application Foundation and Advanced Technology, China (No. 11JCZDJC15300).

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Received 11 October 2011, revised manuscript received 23 December 2011

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Table 1. Preparation conditions of different metals.

Sputtering target	Sputtering pressure (Pa)	Sputtering gas mixture ratio	Sputtering time (min)	Sputtering power (W)
W	1	Ar : O <sub>2</sub> = 30 : 20	30	100
Pt	2	Ar	10	90

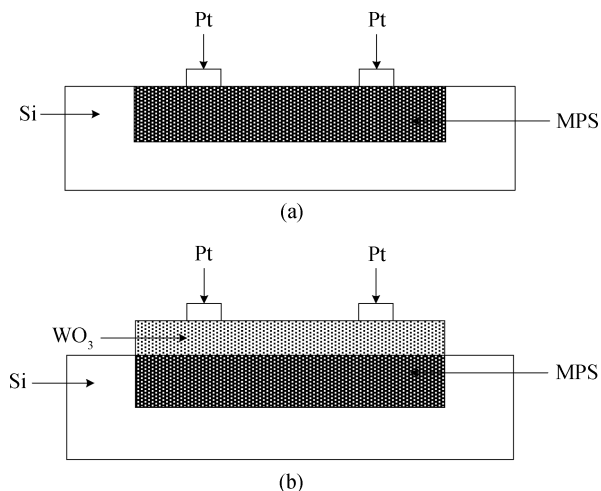


Fig. 1. Schematic diagrams of the (a) MPS and (b) WO<sub>3</sub>/MPS gas sensors.

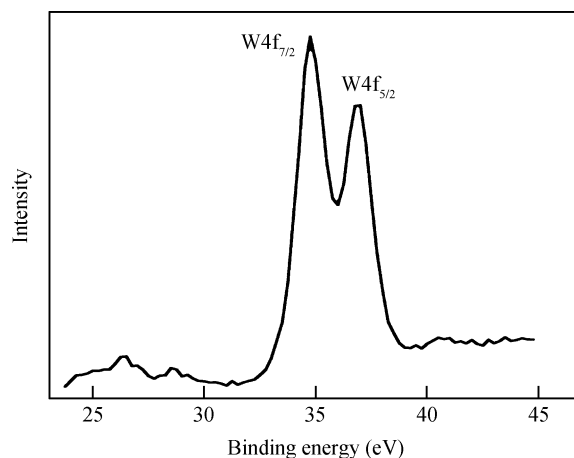


Fig. 3. Binding energy of W4f WO<sub>3</sub>/MPS sample.

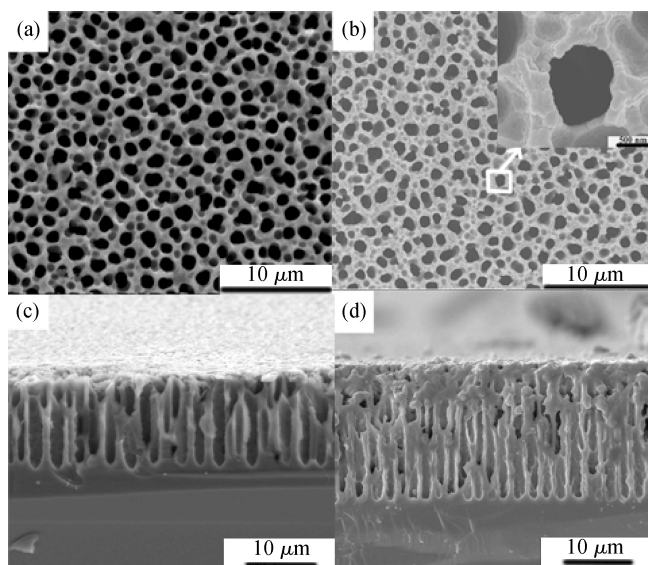


Fig. 2. SEM images of the (a, c) MPS and (b, d) WO<sub>3</sub>/MPS. (a, b) Surface morphology. (c, d) Cross-section morphology.

perature. The sensors were placed in a 30 liter test chamber. The testing gas was directly injected into the chamber to get the desired concentration. The sensor sensitivity (*S*) is defined as  $R_g/R_a$  or  $R_a/R_g$  for reducing or oxidizing gases, respectively, where  $R_a$  is the resistance value in the presence of the ambient atmosphere and  $R_g$  is the resistance value in the presence of the measured species.

### 3. Results and discussion

#### 3.1. Morphology of MPS and WO<sub>3</sub>/MPS samples

Figures 2(a) and 2(b) show the surface morphology images of the MPS and WO<sub>3</sub>/MPS samples with a hole-shaped frame.

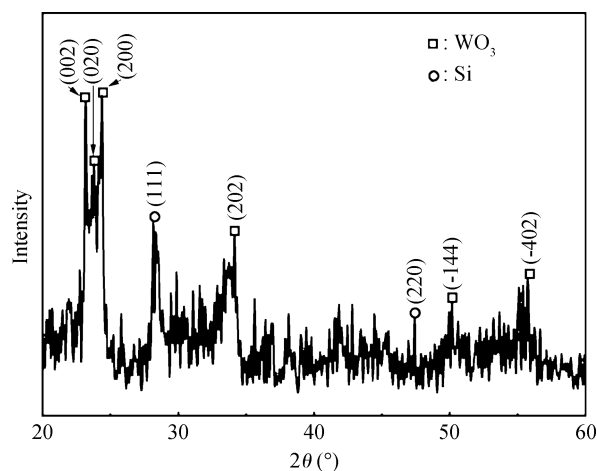


Fig. 4. XRD analysis of WO<sub>3</sub>/MPS sample.

It can be concluded that the average pore size of the MPS is 1.5 μm and WO<sub>3</sub> nano-particles form a semi-continuous thin film on the surface of MPS layer. Figures 2(c) and 2(d) present the cross-section morphology images of the MPS and WO<sub>3</sub>/MPS samples. The typical pore depth is 12 μm and the micropores are cylindrical in shape with a conical termination at the c-Si interface of the anodized wafer (Fig. 2(c)). There is a nano-WO<sub>3</sub> film on the surface of the MPS (Fig. 2(d)). The structure of the MPS is not destroyed by the deposited nano-WO<sub>3</sub> film.

#### 3.2. X-ray photoelectron spectroscopy analysis

Figure 3 shows the binding energy of W4f of the WO<sub>3</sub>/MPS sample. The binding energy of W4f<sub>7/2</sub> and W4f<sub>5/2</sub> are determined to be 34.8 and 37.0 eV, respectively, which do not agree well with values for W<sup>6+</sup> from Ref. [20]. The spectrum shifts towards a lower binding energy; this may be caused

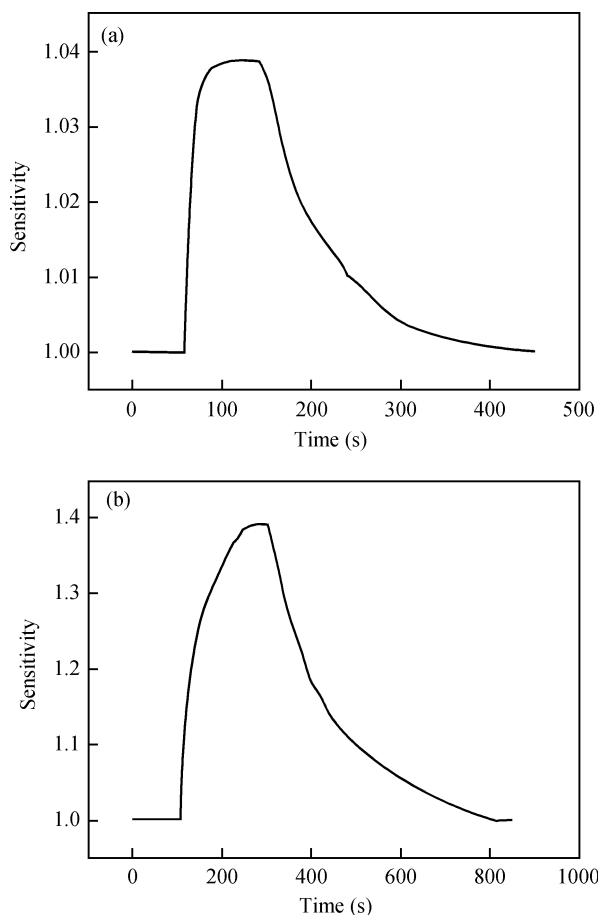


Fig. 5. Responses of (a) MPS and (b)  $\text{WO}_3/\text{MPS}$  gas sensors to 1 ppm  $\text{NO}_2$  at room temperature.

by the contribution from  $\text{W}^{5+}$  or  $\text{W}^{4+}$  states, resulting from oxygen vacancies in the film. It was reported that these states could play important roles in the sensor's performance<sup>[21]</sup>.

### 3.3. X-ray diffraction analysis

Figure 4 shows the XRD pattern of the  $\text{WO}_3/\text{MPS}$  sample. It can be seen that  $\text{WO}_3$  exhibits a triclinic phase (PDF20-1323). There are some diffraction peaks at (002), (020), (200), (022), (-114) and (-402) crystal faces. The strongest peak lies at  $2\theta = 24.4^\circ$ . However, the noise of the XRD pattern is rather high due to the thin thickness and rough surface of the nano- $\text{WO}_3$  film.

### 3.4. Gas sensing properties of MPS and $\text{WO}_3/\text{MPS}$ gas sensors

Figure 5 shows the responses of the MPS and  $\text{WO}_3/\text{MPS}$  gas sensors to 1 ppm  $\text{NO}_2$  at room temperature. The detection sensitivity in the oxidizing gas is greater than 1. It can be concluded that the resistance values of sensors decrease rapidly when  $\text{NO}_2$  is introduced into the measurement chamber. Upon exposing the sensors to air by opening the chamber, the resistance values of the sensors gradually increase to the initial values. The sensors have shown P-type semiconductor gas sensor behavior for oxidizing gas. The sensitivity of the  $\text{WO}_3/\text{MPS}$  gas sensor is much higher than that of the MPS gas sensor. The

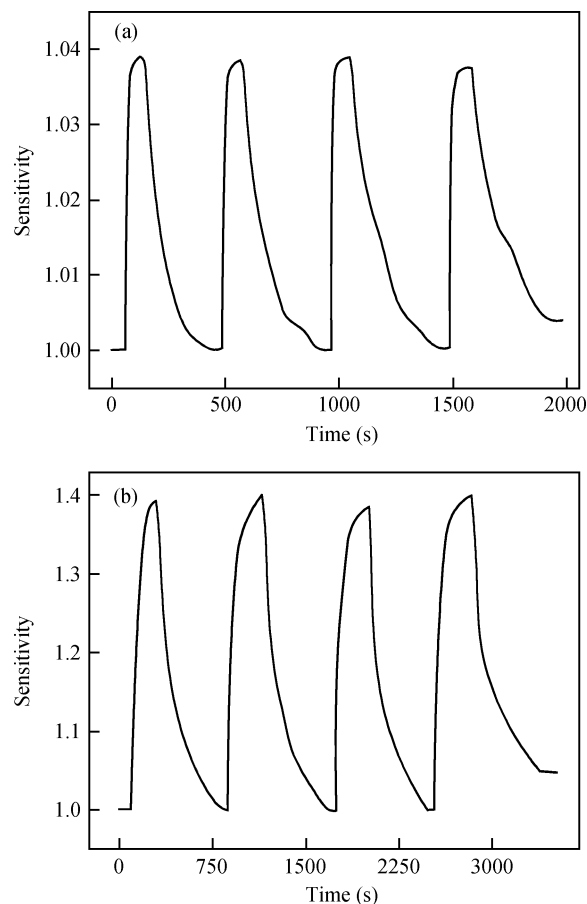


Fig. 6. Dynamic responses of (a) MPS and (b)  $\text{WO}_3/\text{MPS}$  gas sensors to 1 ppm  $\text{NO}_2$  at room temperature.

$\text{WO}_3/\text{MPS}$  gas sensor shows good response-recovery characteristics to 1 ppm  $\text{NO}_2$ . But the response time and recovery time of the  $\text{WO}_3/\text{MPS}$  gas sensor are longer than those of MPS gas sensor since the nano- $\text{WO}_3$  film covers the MPS surface which inhibits the diffusion of the gas.

Figure 6 presents the dynamic responses of MPS and  $\text{WO}_3/\text{MPS}$  gas sensors to 1 ppm  $\text{NO}_2$  at room temperature. The average sensitivity is 1.04 and 1.40 for MPS gas sensor and  $\text{WO}_3/\text{MPS}$  gas sensor, respectively. The overall variations in sensor sensitivity, response time and recovery time are very small for both gas sensors, which indicates good repeatability of the MPS and  $\text{WO}_3/\text{MPS}$  gas sensors to 1 ppm  $\text{NO}_2$ . Moreover, after four times repeating, the resistance values of the MPS and  $\text{WO}_3/\text{MPS}$  gas sensors can almost recover to their initial values, which shows good reproducibility to 1 ppm  $\text{NO}_2$ .

Figure 7 shows the responses of MPS and  $\text{WO}_3/\text{MPS}$  gas sensors to different  $\text{NO}_2$  concentrations at room temperature. From this figure, it can be seen that the sensitivity values of the  $\text{WO}_3/\text{MPS}$  gas sensor upon exposure to 1, 10, 25 and 50 ppm  $\text{NO}_2$  are 1.40, 5.01, 9.01 and 14.4, while those of the MPS gas sensor are 1.04, 1.18, 1.25 and 1.34, respectively. All of the sensitivity values of the gas sensors increase with the mounting up of the  $\text{NO}_2$  concentration. It also can be seen that the  $\text{WO}_3/\text{MPS}$  gas sensor has higher sensitivity than that of the MPS gas sensor in each  $\text{NO}_2$  gas concentration.

As  $\text{NO}_2$  is an oxidizing gas, it causes local and partial oxidation of the MPS surface, which causes the increase of defect

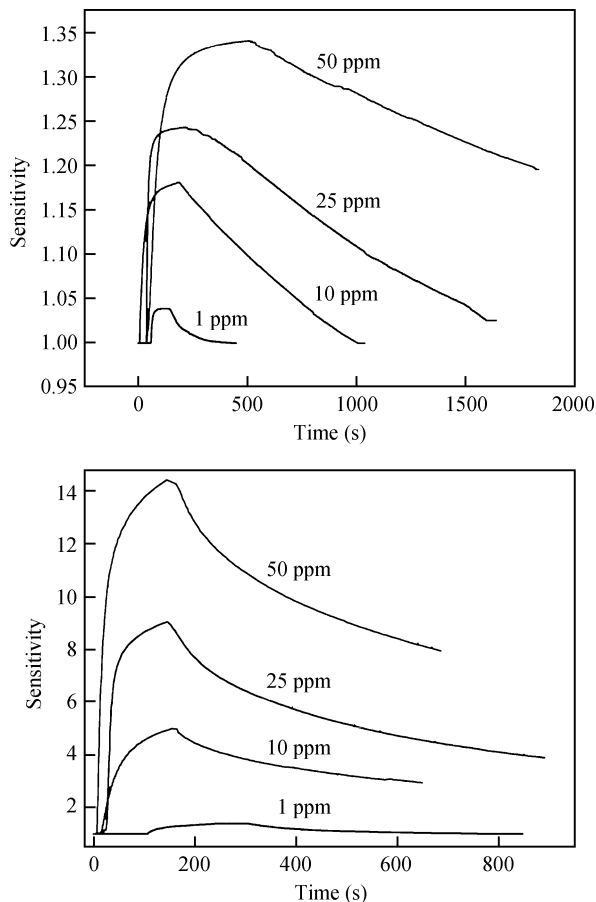


Fig. 7. Responses of (a) MPS and (b) WO<sub>3</sub>/MPS gas sensors to different NO<sub>2</sub> concentrations at room temperature.

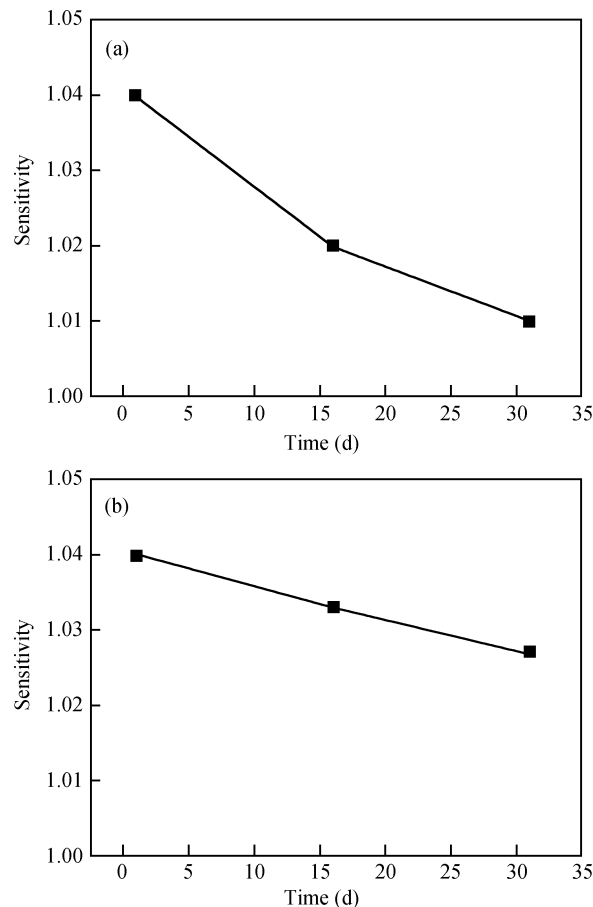


Fig. 8. Sensitivity of (a) MPS and (b) WO<sub>3</sub>/MPS gas sensors to 1 ppm NO<sub>2</sub> for different storage days.

density. These defects play the role of electron traps, into which electrons relax<sup>[22, 23]</sup>. Therefore, it seems that the electron traps created by partial oxidation of MPS in the presence of NO<sub>2</sub> are responsible for the increase of free charge carriers in P-type MPS. Since WO<sub>3</sub> behaves as an n-type semiconductor gas sensor which is controlled by the surface conductance<sup>[24, 25]</sup>, the hetero-structure (n-WO<sub>3</sub>/p-MPS) is formed at the interface between WO<sub>3</sub> and MPS. In the hetero-structure, there exists a depletion layer and associated potential barrier. The concentration of free carriers in the MPS increases when MPS adsorbs NO<sub>2</sub>. The width of the depletion layer gets smaller and the potential barrier gets lower. It may bring in additional increasing part of the current. This change may explain the improvement in responsiveness shown by WO<sub>3</sub>/MPS gas sensor. Moreover, WO<sub>3</sub> is a good gas sensing material for NO<sub>2</sub>. It has good selectivity to NO<sub>2</sub><sup>[26, 27]</sup>. In the combined structure, the improvement of gas sensing properties observed may be attributed to the effects of WO<sub>3</sub> as a catalyst on the surface of the MPS.

Although the sensitivity of the WO<sub>3</sub>/MPS gas sensor to NO<sub>2</sub> is higher than that of MPS gas sensor, the baseline shifting of the gas sensor is more obviously for WO<sub>3</sub>/MPS gas sensor, especially at high concentrations (above 10 ppm). The nano-WO<sub>3</sub> which inhibits the diffusion of the gas results in poor recover characteristic at relative high NO<sub>2</sub> concentrations.

The long-term stability of the sensors was investigated by testing the sensitivity to 1 ppm NO<sub>2</sub> for different storage days. The results are shown in Fig. 8. On one hand the sensitivity of

the sensors shows evident changes over 30 days storage which indicates that the long-term stability of the gas sensors is not very good. On the other hand, it also can be seen that the sensitivity of the WO<sub>3</sub>/MPS gas sensor changes more slowly than that of the MPS gas sensor. The nano-WO<sub>3</sub> may make surface passivation of the MPS, which causes a better long-term stability of WO<sub>3</sub>/MPS gas sensor.

To examine the selectivity of MPS and WO<sub>3</sub>/MPS gas sensors, the sensors have been tested to other two gases (50 ppm). The results are shown in Fig. 9, revealing that the WO<sub>3</sub>/MPS gas sensor exhibits the best sensitivity to NO<sub>2</sub> with a value of 14.4, while MPS gas sensor exhibits the best sensitivity to NH<sub>3</sub> with a value of 4.2. The selectivity of the MPS to NO<sub>2</sub> is modified by deposited nano-WO<sub>3</sub> film.

#### 4. Conclusions

MPS layers were obtained by electrochemical dissolution in a double-tank cell on the surface of the monocrystalline P-type silicon. The MPS layer is with a depth of 12 μm and a normal size of the pore about 1.5 μm. The nano-WO<sub>3</sub> films prepared by DC reactive magnetron sputtering were deposited on the MPS layer. Nano-WO<sub>3</sub> film exhibits triclinic phase. XPS test shows that the valence of the W is consisted of W<sup>6+</sup>, W<sup>5+</sup> and W<sup>4+</sup> states.

The gas sensing properties measurements indicate that low concentration of 1 ppm NO<sub>2</sub> can be detected even when the

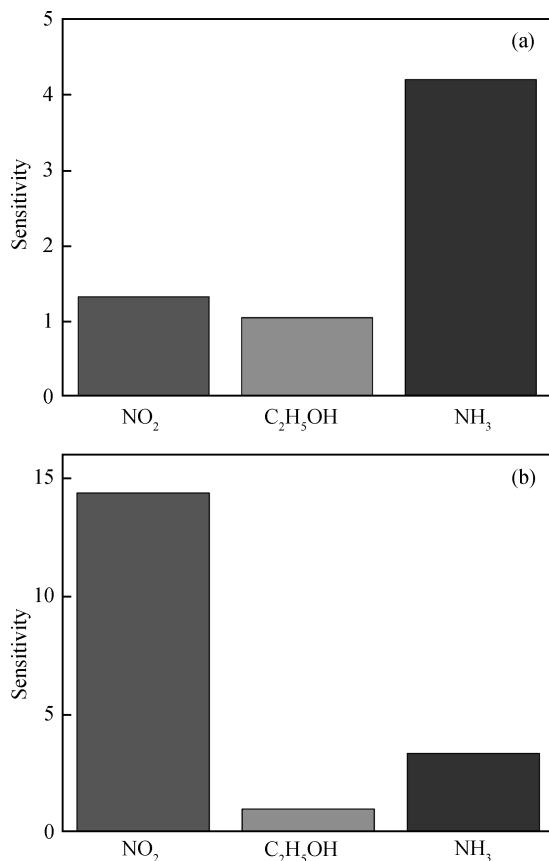


Fig. 9. Sensitivity of (a) MPS and (b) WO<sub>3</sub>/MPS gas sensors to 50 ppm various gases at room temperature.

WO<sub>3</sub>/MPS sensor is operated at room temperature. The sensitivity of the WO<sub>3</sub>/MPS gas sensor is much higher than that of MPS gas sensor in each NO<sub>2</sub> concentration. The long-term stability and selectivity are also improved.

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